



12V PNP LOW SATURATION TRANSISTOR AND 40V, 1A SCHOTTKY DIODE COMBINATION DUAL

Features

- **PNP** Transistor
 - $V_{CEO} = -12V$
 - $R_{SAT} = 65m\Omega$
 - $I_{\rm C} = -4A$
- Schottky Diode
 - $V_R = 40V$
 - $V_{F} = 500 mv (@1A)$
 - $I_{\rm C} = 1 A$
- I_C = -4A Continuous Collector Current
- Low Saturation Voltage (-140mV @ 1A)
- hFE characterized up to -10A
- Low V_F, fast switching Schottky
- Lead, Halogen, and Antimony Free/RoHS Compliant (Note 1) •
- "Green" Devices (Note 2)

Mechanical Data

- Case: DFN3020B-8 .
- Terminals: Pre-Plated NiPdAu leadframe
- Nominal package height: 0.8mm
- UL Flammability Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Solderable per MIL-STD-202, Method 208
- Weight: 0.013 grams (approximate)

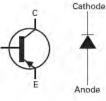
Applications

- DC DC Converters
- Charging circuits
- Mobile phones
- Motor control

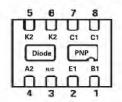
DFN3020B-8



Top View



Device symbol



Pin Configuration

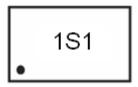
Ordering Information

Product	Status	Package	Marking	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXTPS717MCTA	Active	DFN3020B-8	1S1	7	8	3000

Notes: 1. No purposefully added lead. Halogen and Antimony Free.

2. Diodes Inc's "Green" Policy can be found on our website https://www.diodes.com

Marking Information



1S1 = Product type Marking Code Dot Denotes Pin 1



Maximum Ratings, Transistor

Parameter	Symbol	Limit	Unit
Collector-Base Voltage	V _{CBO}	-20	V
Collector-Emitter Voltage	V _{CEO}	-12	V
Emitter-Base Voltage	V _{EBO}	-7.5	V
Peak Pulse Current	I _{CM}	-12	А
Continuous Collector Current (Notes a and f)	Ι _C	-4	А
Continuous Collector Current (Notes b and f)	Ι _C	-4.4	А
Base Current	Ι _Β	1	А

Thermal Characteristics, Transistor

Characteristic	Symbol	Value	Unit
Power Dissipation at $T_A = 25^{\circ}C$ (Notes a and f) Linear Derating Factor	PD	1.5 12	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes b and f) Linear Derating Factor	P _D	2.45 19.6	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes c and f) Linear Derating Factor	P _D	1 8	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes d and f) Linear Derating Factor	P _D	1.13 9	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes d and g) Linear Derating Factor	PD	1.7 13.6	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes e and g) Linear Derating Factor	PD	3 24	W mW/°C
Junction to Ambient (Notes a and f)	R _{0JA}	83	°C/W
Junction to Ambient (Notes b and f)	R _{AJA}	51	°C/W
Junction to Ambient (Notes c and f)	R _{eJA}	125	°C/W
Junction to Ambient (Notes d and f)	R _{0JA}	111	°C/W
Junction to Ambient (Notes d and g)	R _{0JA}	73.5	°C/W
Junction to Ambient (Notes e and g)	R _{0JA}	41.7	°C/W
Junction Temperature	TJ	150	°C
Operating and Storage Temperature Range	T _{STG}	-55 to +150	°C

Notes: a. For a dual device surface mounted on 8 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

b. Measured at t <5 secs for a dual device surface mounted on 8 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

c. For a dual device surface mounted on 8 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with minimal lead connections only.

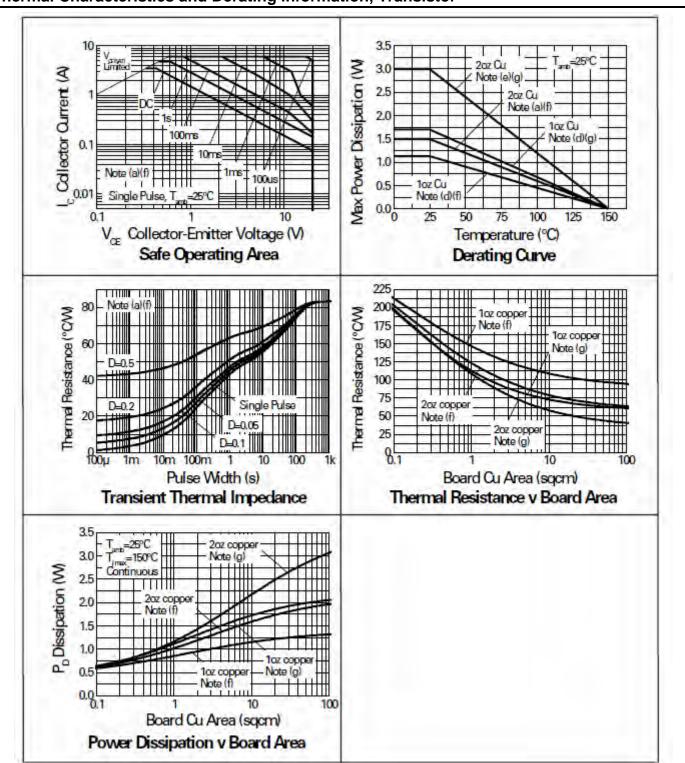
d. For a dual device surface mounted on 10 sq cm single stated 1 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

e. For a dual device surface mounted on 85 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

f. For a dual device with one active die.

g. For dual device with 2 active die running at equal power.





Thermal Characteristics and Derating information, Transistor



Maximum Ratings, Schottky Diode

Parameter	Symbol	Limit	Unit
Continuous Reverse Voltage	V _R	40	V
Forward Voltage @ I _F = 1000mA (typ)	V _F	425	mV
Forward Current	l _F	1850	mA
Average Peak Forward Current D=50%	IFAV	3	A
Non Repetitive Forward Current t≤ 100µs	I	12	A
t≤ 10ms	IFSM	7	A

Thermal Characteristics, Schottky Diode

Characteristic	Symbol	Value	Unit
Power Dissipation at $T_A = 25^{\circ}C$ (Notes a and f) Linear Derating Factor	PD	1.2 12	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes b and f) Linear Derating Factor	PD	2 20	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes c and f) Linear Derating Factor	PD	0.8 8	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes d and f) Linear Derating Factor	PD	0.9 9	W mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes d and g) Linear Derating Factor	PD	1.36 13.6	₩ mW/°C
Power Dissipation at $T_A = 25^{\circ}C$ (Notes e and g) Linear Derating Factor	PD	2.4 24	₩ mW/°C
Junction to Ambient (Notes a and f)	R _{θJA}	83	°C/W
Junction to Ambient (Notes b and f)	R _{θJA}	51	°C/W
Junction to Ambient (Notes c and f)	R _θ JA	125	°C/W
Junction to Ambient (Notes d and f)	R _{θJA}	111	°C/W
Junction to Ambient (Notes d and g)	R _{θJA}	73.5	°C/W
Junction to Ambient (Notes e and g)	R _{θJA}	41.7	°C/W
Junction Temperature	TJ	125	°C
Operating and Storage Temperature Range	T _{STG}	-55 to +150	°C

a. For a dual device surface mounted on 8 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

b. Measured at t <5 secs for a dual device surface mounted on 8 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.</p>

c. For a dual device surface mounted on 8 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with minimal lead connections only.

d. For a dual device surface mounted on 10 sq cm single sided 1 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

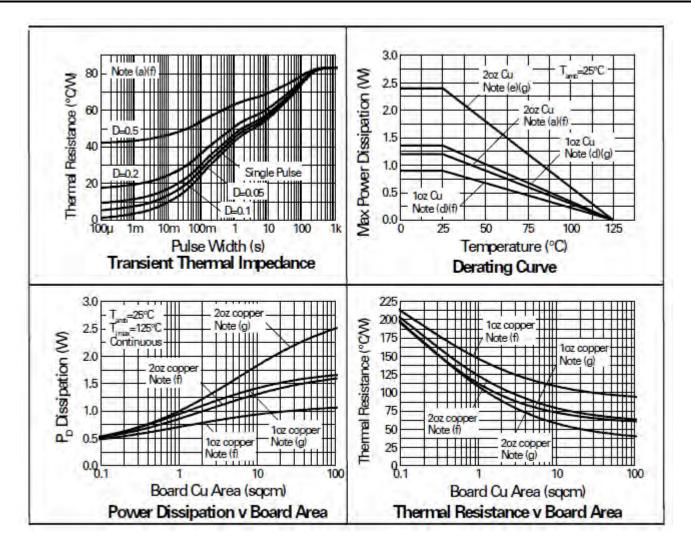
e. For a dual device surface mounted on 85 sq cm single sided 2 oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

f. For a dual device with one active die.

Notes:

g. For dual device with 2 active die running at equal power.





Thermal Characteristics and Derating information, Schottky Diode



Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
Collector-Base Breakdown Voltage	V _{(BR)CBO}	-20	-35	-	V	I _C = -100μA
Collector-Emitter Breakdown Voltage (Note 3)	V _{(BR)CEO}	-12	-25	-	V	I _C = -10mA
Emitter-Base Breakdown Voltage	V _{(BR)EBO}	-7.5	-8.5	-	V	I _E = -100μA
Collector Cutoff Current	I _{СВО}	-	-	-25	nA	V _{CB} = -16V
Emitter Cutoff Current	I _{EBO}	-	-	-25	. nA	$V_{EB} = -6V$
Collector Emitter Cutoff Current	ICES	-	-	-25	nA	V _{CES} = -10V
Static Forward Current Transfer Ratio (Note 3)	hfe	300 300 180 60 45 -	475 450 275 100 70 -10	- - - - - - 17	-	$\begin{split} I_{C} &= -10 \text{mA}, \ V_{CE} &= -2 \text{V} \\ I_{C} &= -100 \text{mA}, \ V_{CE} &= -2 \text{V} \\ I_{C} &= -2.5 \text{A}, \ V_{CE} &= -2 \text{V} \\ I_{C} &= -8 \text{A}, \ V_{CE} &= -2 \text{V} \\ I_{C} &= -10 \text{A}, \ V_{CE} &= -2 \text{V} \\ I_{C} &= -0.1 \text{A}, \ I_{B} &= -10 \text{mA} \\ I_{C} &= -0.1 \text{A}, \ I_{B} &= -10 \text{mA} \end{split}$
Collector-Emitter Saturation Voltage (Note 3)	V _{CE(sat)}		-100 -100 -195 -240	-140 -150 -300 -300	mV	$\begin{split} I_{C} &= -1A, \ I_{B} = -10 mA \\ I_{C} &= -1.5A, \ I_{B} = -50 mA \\ I_{C} &= -3A, \ I_{B} = -50 mA \\ I_{C} &= -4A, \ I_{B} = -150 mA \end{split}$
Base-Emitter Turn-On Voltage (Note 3)	V _{BE(on)}	-	-0.87	-0.95	V	$I_{C} = -4A, V_{CE} = -2V$
Base-Emitter Saturation Voltage (Note 3)	V _{BE(sat)}	-	-0.97	-1.05	V	I_{C} = -4A, I_{B} = -150mA
Output Capacitance	Cobo	-	21	30	pF	V _{CB} = -10V, f = 1MHz
Transition Frequency	f _T	100	110	-	MHz	$V_{CE} = -10V, I_C = -50mA, f = 100MHz$
Turn-on Time	t _{on}	-	70	-	ns	$V_{CC} = -6V, I_{C} = -2A$
Turn-off Time	t _{off}	-	130	-	ns	$I_{B1} = I_{B2} = -50 \text{mA}$

Electrical Characteristics, Transistor @TA = 25°C unless otherwise specified

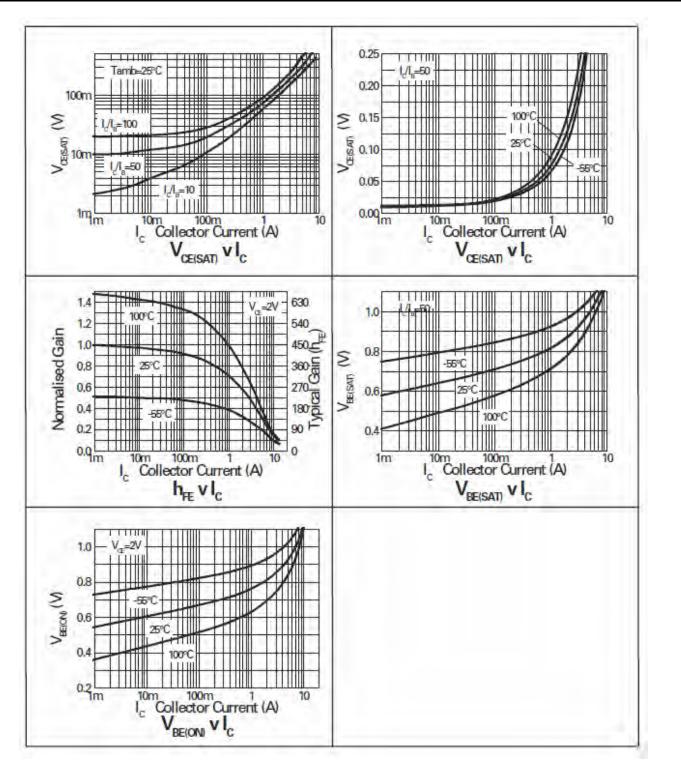
Electrical Characteristics, Schottky Diode @T_A = 25°C unless otherwise specified

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
Reverse Breakdown Voltage	V _{(BR)R}	40	60	-	V	I _R = -300μA
Forward Voltage (Note 3)	V _F	- - - - - - - -	240 265 305 355 390 425 495 420	270 290 340 400 450 500 600 -	mV	$I_{F} = 50mA$ $I_{F} = 100mA$ $I_{F} = 250mA$ $I_{F} = 500mA$ $I_{F} = 750mA$ $I_{F} = 1000mA$ $I_{F} = 1500mA$ $I_{F} = 1000mA, T_{A} = 100^{\circ}C$
Reverse Current	I _R	-	50	100	μA	$V_R = 30V$
Diode Capacitance	C _D	-	25	-	pF	V _R = 25V, f = 1MHz
Reverse Recovery Time	trr	-	12	-	ns	switched from $I_F = 500mA$ to $I_R = 500mA$ Measured at $I_R = 50mA$

Notes: 3 . Measured under pulsed conditions.

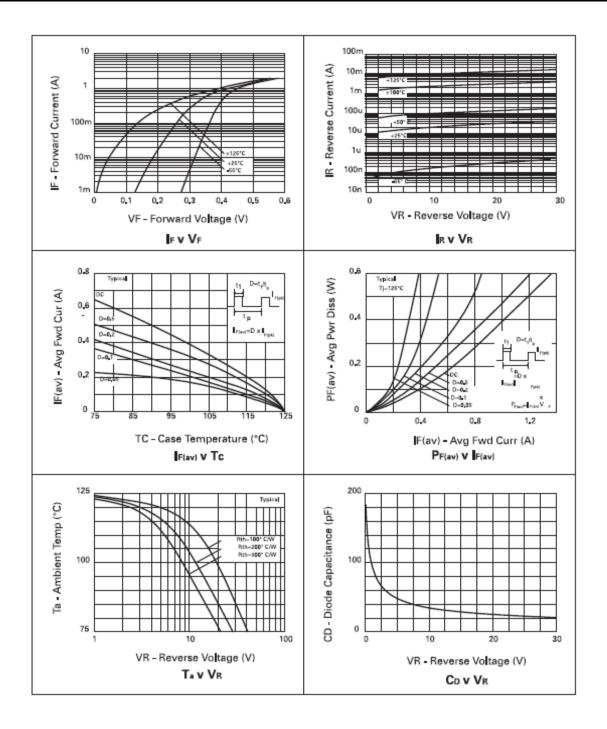


Typical Characteristics, Transistor





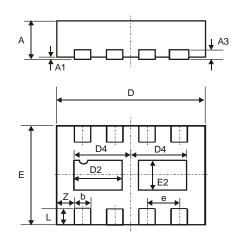
Typical Characteristics, Schottky Diode





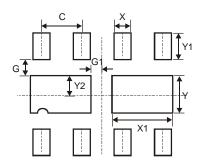


Package Outline Dimensions



DFN3020B-8						
Dim	Min	Max	Тур			
Α	0.77	0.83	0.80			
A1	0	0.05	0.02			
A3	-	-	0.15			
b	0.25	0.35	0.30			
D	2.95	3.075	3.00			
D2	0.82	1.02	0.92			
D4	1.01	1.21	1.11			
е	-	-	0.65			
Е	1.95	2.075	2.00			
E2	0.43	0.63	0.53			
L	0.25	0.35	0.30			
Ζ	-	-	0.375			
All I	Dimens	sions ir	n mm			

Suggested Pad Layout



Dimensions	Value (in mm)				
С	0.650				
G	0.285				
G1	0.090 0.400 1.120				
Х					
X1					
Y	0.730				
Y1	0.500				
Y2	0.365				



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